

OptiMOS® Chip data sheet

Feature

- N-Channel
- Enhancement mode
- 175°C operating temperature
- Avalanche rated
- dv/dt rated
- Integrated gate resistance for easy parallel connection

| | | |
|--------------|-------|-----------------|
| V_{DS} | 75 | V |
| $R_{DS(on)}$ | 4.2 | mΩ |
| Die size | 7 x 6 | mm ² |
| Thickness | 175 | μm |

Ordering Code

| | |
|----------------------|--------------|
| unsawn wafer on foil | on request |
| sawn wafer on foil | Q67061-S7146 |
| surf tape | on request |

DESCRIPTION

- Assembly by epoxy die bonding or soldering
- AQL 1.5 for visual inspection according to failure catalog A67207-A7001-A001 issue C on 100% measured wafer
- Storage of chips and wafer according technical guideline 14 Doc. No. A66003-R14-T1-B-35

Maximum Ratings, at $T_j = 25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|---|----------------|-------------|------|
| Continuous drain current ¹⁾²⁾ $T_C=25\text{ °C}$ | I_D | 227 | A |
| Avalanche energy, single pulse ¹⁾ $I_D=80\text{ A}, V_{DD}=25\text{ V}, R_{GS}=25\text{ Ω}$ | E_{AS} | 1070 | mJ |
| Repetitive avalanche energy, limited by T_{jmax} ¹⁾²⁾ | E_{AR} | 50 | mJ |
| Gate source voltage | V_{GS} | ±20 | V |
| Additional gate resistance | R_G | 5 ±20% | Ω |
| Operating and storage temperature | T_j, T_{stg} | -55... +175 | °C |

¹⁾ Defined by design. Not subject to production test.

²⁾ Calculated with $R_{thJC} = 0.3\text{ K/W}$

Electrical Characteristics, at $T_j = 25\text{ °C}$, unless otherwise specified

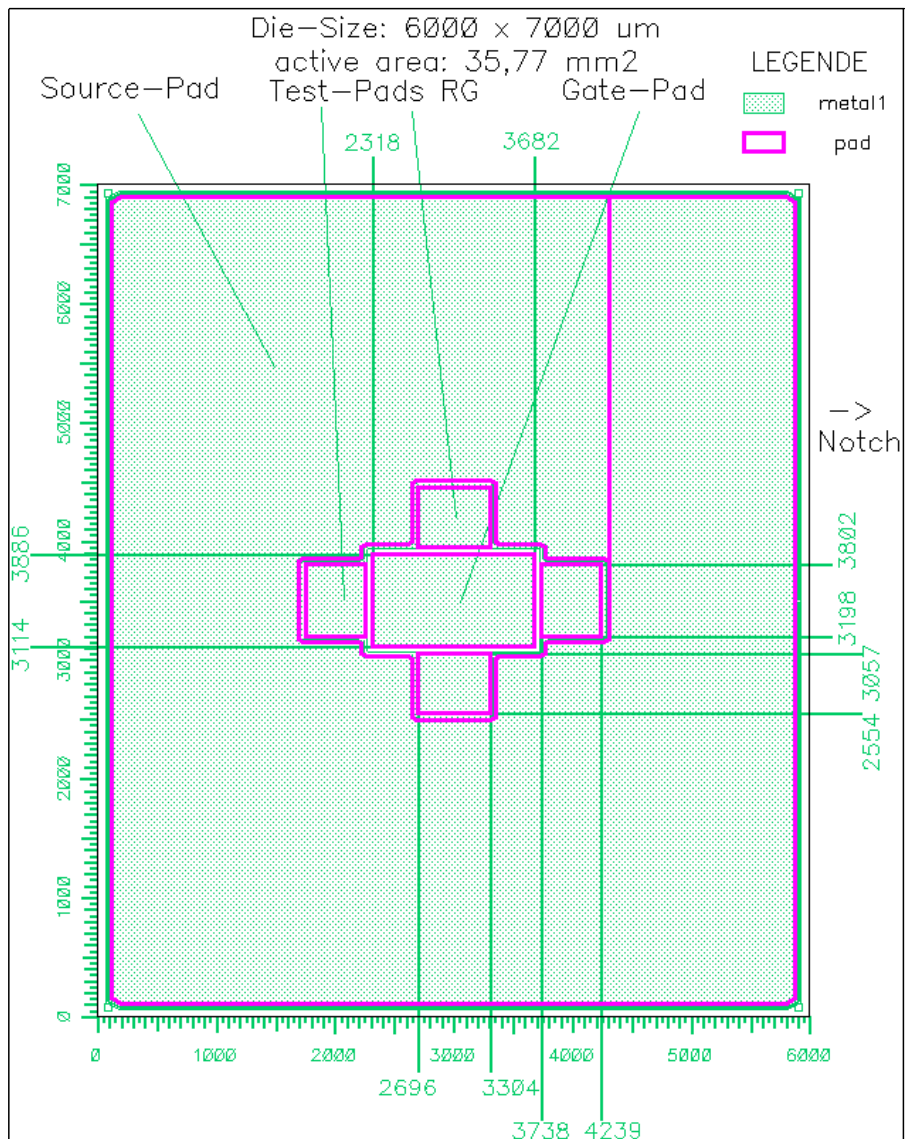
| Parameter | Symbol | Values | | | Unit |
|---|---------------|--------|------|------|------------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$ | $V_{(BR)DSS}$ | 75 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 250\text{ }\mu A$ | $V_{GS(th)}$ | 2.1 | 3 | 4 | |
| Zero gate voltage drain current $V_{DS}=75V, V_{GS}=0V, T_j=25\text{ °C}$ $V_{DS}=75V, V_{GS}=0V, 125\text{ °C, }^1)$ | I_{DSS} | - | 0.01 | 1 | μA |
| Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$ | I_{GSS} | - | 1 | 100 | nA |
| On-state resistance ¹⁾ $V_{GS}=10V, I_D=134A$ | $R_{DS(on)}$ | - | 3.7 | 4.2 | m Ω |
| Dynamic Characteristics¹⁾ | | | | | |
| Gate to source charge $V_{DD}=60V, I_D=80A$ | Q_{gs} | - | 27 | 36 | nC |
| Gate to drain charge $V_{DD}=60V, I_D=80A$ | Q_{gd} | - | 82 | 123 | |
| Gate charge total $V_{DD}=60V, I_D=80A, V_{GS}=0\text{ to }10V$ | Q_g | - | 189 | 251 | |
| Reverse Diode¹⁾ | | | | | |
| Inverse diode forward voltage $V_{GS}=0V, I_F=80A$ | V_{SD} | - | 0.9 | 1.3 | V |

¹⁾Defined by design. Not subject to production test.

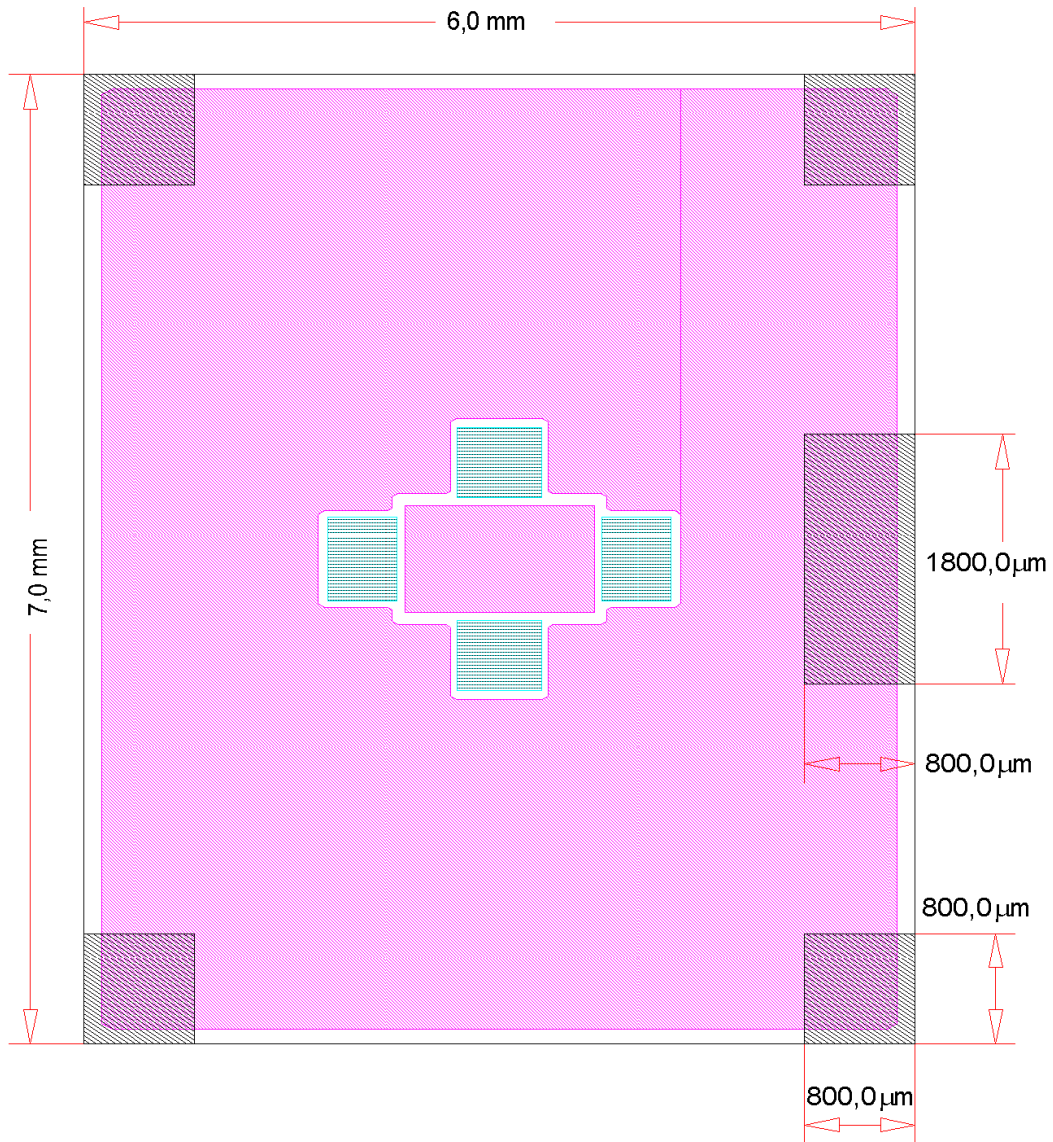
CHIP Parameters



| | |
|------------------------|--------------------------|
| Saw street width | - |
| Passivation frontside | Nitride |
| Metalization frontside | 5 μ AlSiCu |
| Metalization gate pad | AlSiCu |
| Metalization backside | Ni-Ag System |
| Die bond | applicable: soft or glue |
| Wire bond | Al wedge-wedge |

Chip - Layout:



Additional information for bonding:



-  Area for testing purposes: bonding here is not recommended
-  Area of integrated gate resistance covered with Al metallization: no contact with gate bond wires allowed in order to prevent short circuit of gate resistance

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Further information

Please notice that the part number is BSIPC42S2N08, for simplicity the device is referred to by the term SIPC42S2N08 throughout this documentation.